

<IGBT Modules>

## CM300DY-24T

**HIGH POWER SWITCHING USE INSULATED TYPE** 



dual switch (half-bridge)

Collector current Ic ..... 3 0 0 A Collector-emitter voltage VCES ...... 1 2 0 0 V Maximum junction temperature T<sub>vjmax</sub> .......

- •Flat base type
- Copper base plate (Nickel-plating)
- •Tin-plating signal terminals
- •RoHS Directive compliant
- •UL Recognized under UL1557, File No.E323585

#### **APPLICATION**

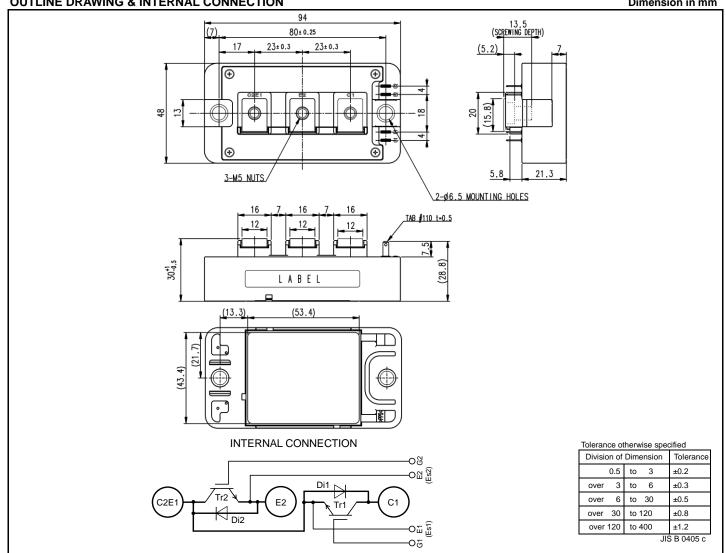
AC Motor Control, Motion/Servo Control, Power supply, etc.

**OPTION** (Below options are available.)

- ●PC-TIM (Phase Change Thermal Interface Material) pre-apply
- Vcesat selection for parallel connection

#### **OUTLINE DRAWING & INTERNAL CONNECTION**

Dimension in mm



1

## HIGH POWER SWITCHING USE

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## MAXIMUM RATINGS ( $T_{vj}$ =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1200	V	
$V_{GES}$	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Collector ourrent	DC, T <sub>C</sub> =125 °C (Note2, 4)	300	۸	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	600	А	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	3260	W	
I <sub>E</sub> (Note1)	Facilities accurated	DC (Note2)	300	^	
I <sub>ERM</sub> (Note1)	Emitter current	Pulse, Repetitive (Note3)	600	Α	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T <sub>jmax</sub>	Maximum junction temperature	Instantaneous event (overload)	175	°C	
T <sub>Cmax</sub>	Maximum case temperature	(Note4)	125		
Tjop	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +125		

## ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symbol	ltom	Conditions		Limits			l le !t	
Symbol	Item			Min.	Тур.	Max.	Unit	
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited	-	-	1.0	mA		
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited	-	-	0.5	μΑ		
V <sub>GE(th)</sub>	Gate-emitter threshold voltage	I <sub>C</sub> =30 mA, V <sub>CE</sub> =10 V	5.4	6.0	6.6	V		
		I <sub>C</sub> =300 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	1.70	2.00	V	
V <sub>CEsat</sub> (Terminal)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	1.95	-		
(Terminal)	Callantar are the continue time college	(Note5)	T <sub>vj</sub> =150 °C	-	2.00	-		
	Collector-emitter saturation voltage	I <sub>C</sub> =300 A,	T <sub>vj</sub> =25 °C	-	1.55	1.80		
V <sub>CEsat</sub>		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	1.75	-	V	
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.80	-	1	
Cies	Input capacitance			-	-	61.5		
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		-	-	1.8	nF	
Cres	Reverse transfer capacitance	7	-	-	0.8			
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =600 V, I <sub>C</sub> =300 A, V <sub>GE</sub> =15 V		-	2.0	-	μC	
t <sub>d(on)</sub>	Turn-on delay time	Vcc=600 V, Ic=300 A, V <sub>GE</sub> =±15 V,		-	-	500	- ns	
tr	Rise time			-	-	150		
t <sub>d(off)</sub>	Turn-off delay time			-	-	600		
t <sub>f</sub>	Fall time	R <sub>G</sub> =1.1 Ω, Inductive load		-	-	300	1	
		I <sub>E</sub> =300 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	1.80	2.20		
V <sub>EC</sub> (Note.1)		Refer to the figure of test circuit T	T <sub>vj</sub> =125 °C	-	1.95	-	V	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	1.95	-		
	- Emitter-collector voltage	I <sub>E</sub> =300 A,	T <sub>vj</sub> =25 °C	-	1.65	2.00		
V <sub>EC</sub> (Note.1)		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	1.65	-	V	
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.65	-	1	
t <sub>rr</sub> (Note1)	Reverse recovery time	V <sub>CC</sub> =600 V, I <sub>E</sub> =300 A, V <sub>GE</sub> =±15 V,	1	-	-	400	ns	
Q <sub>rr</sub> (Note1)	Reverse recovery charge	$R_G=1.1 \Omega$ , Inductive load		-	30	-	μC	
Eon	Turn-on switching energy per pulse	V <sub>CC</sub> =600 V, I <sub>C</sub> =I <sub>E</sub> =300 A,		-	27.9	-		
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}=\pm 15 \text{ V}, R_{G}=1.1 \Omega, T_{vj}=150 \text{ °C},$		-	29.9	-	m.	
E <sub>rr</sub> (Note1)	Reverse recovery energy per pulse	Inductive load	-	18.3	-	m.		
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25	°C (Note4)	-	0.3	-	mΩ	
r <sub>g</sub>	Internal gate resistance	Per switch	-	1.5	-	Ω		

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#### HIGH POWER SWITCHING USE

#### INSULATED TYPE

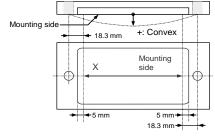
#### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions -		Limits			Unit
Symbol	item			Min.	Тур.	Max.	Offic
$R_{th(j-c)Q}$	→ Thermal resistance	Junction to case, per Inverter IGBT (Note4)		-	-	46	K/kW
R <sub>th(j-c)D</sub>		Junction to case, per Inverter FWD (Note4)		-	-	81	
D	Contact thermal resistance	Case to heat sink,	Thermal grease applied (Note4, 6)	ı	24	1	K/kW
$R_{th(c-s)}$	Contact triefmai resistance	per 1 module,	PC-TIM applied (Note4, 7)	-	6.3	-	r/KVV

#### **MECHANICAL CHARACTERISTICS**

Symbol	Item	Conditions			Limits		Unit	
	item	Conditions		Min.	Тур.	Max.		
M <sub>t</sub>	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N⋅m	
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m	
٨	Creepage distance	Terminal to terminal		18	-	-	mm	
d <sub>s</sub>		Terminal to base plate		21.1	-	-		
da	Clearance	Terminal to terminal		9.6 -		-	m.m.	
	Clearance	Terminal to base plate		16.7	-	-	mm	
ec	Flatness of base plate	On the centerline (Note8)		±0	-	+200	μm	
m	mass	-		-	155	-	g	

- \*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).
  - 2. Junction temperature  $(T_{\nu j})$  should not increase beyond  $T_{\nu j\,m\,a\,x}$  rating.
  - 3. Pulse width and repetition rate should be such that the device junction temperature (T<sub>vj</sub>) dose not exceed T<sub>vjmax</sub> rating.
  - 4. Case temperature (T<sub>C</sub>) and heat sink temperature (T<sub>S</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
  - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
  - 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =0.9 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
  - 7. Typical value is measured by using PC-TIM of  $\lambda$ =3.4 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
  - 8. The base plate (mounting side) flatness measurement points (X) are shown in the following figure.



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HIGH POWER SWITCHING USE

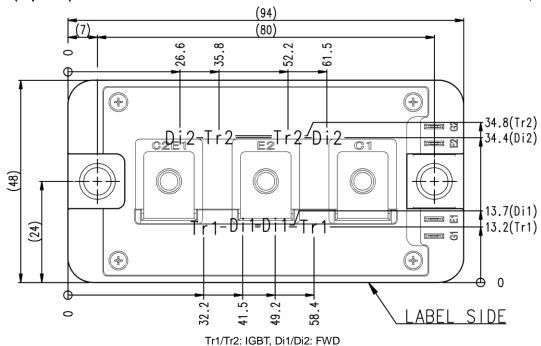
INSULATED TYPE

#### **RECOMMENDED OPERATING CONDITIONS**

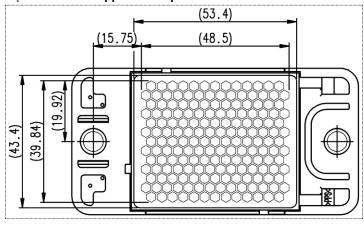
Symbol	Item	Conditions	Limits			Unit
	item		Min.	Тур.	Max.	Offic
V <sub>CC</sub>	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	850	V
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	1.1	-	22	Ω

#### **CHIP LOCATION (Top view)**

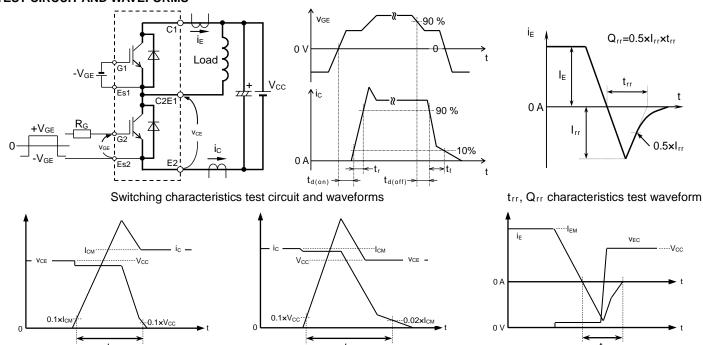
Dimension in mm, tolerance: ±1 mm



Option: PC-TIM applied baseplate outline



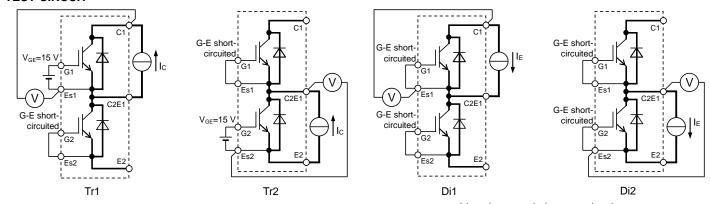
#### **TEST CIRCUIT AND WAVEFORMS**



IGBT Turn-off switching energy Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

#### **TEST CIRCUIT**

IGBT Turn-on switching energy



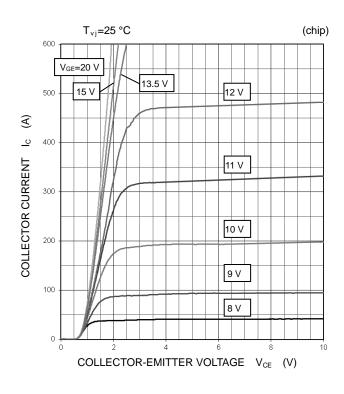
V<sub>CEsat</sub> characteristics test circuit

V<sub>EC</sub> characteristics test circuit

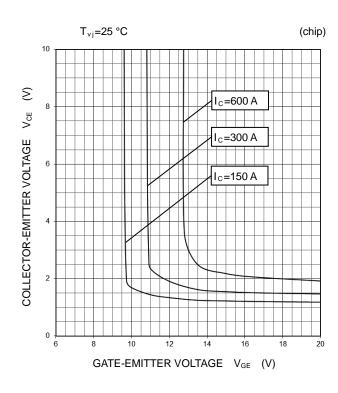
FWD Reverse recovery energy

#### **PERFORMANCE CURVES**

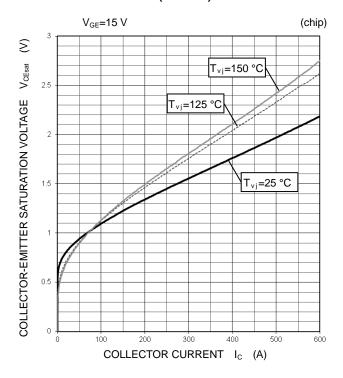
# OUTPUT CHARACTERISTICS (TYPICAL)



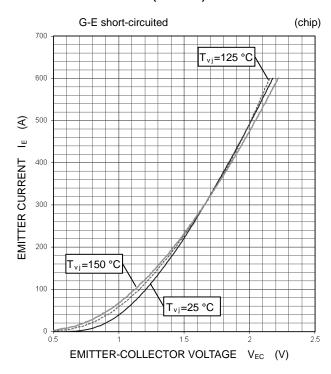
# COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS (TYPICAL)



#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)

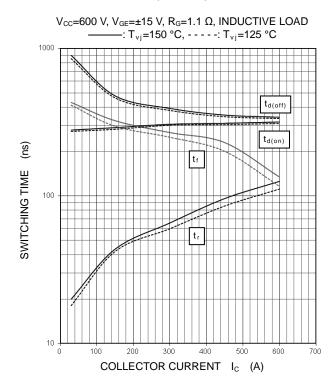


#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

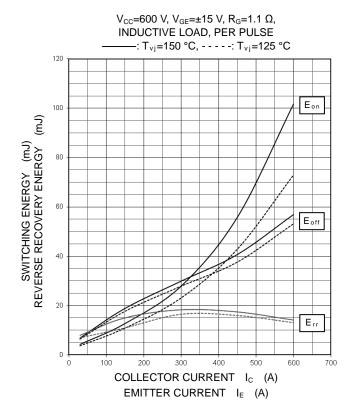


#### **PERFORMANCE CURVES**

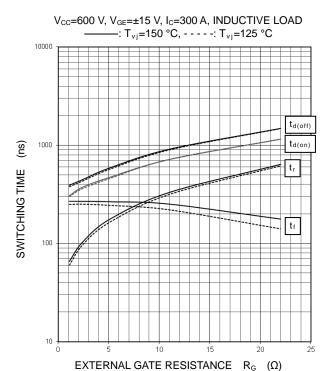
# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



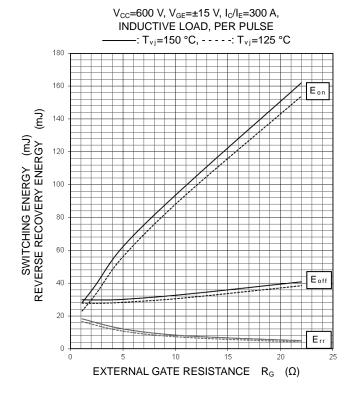
# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



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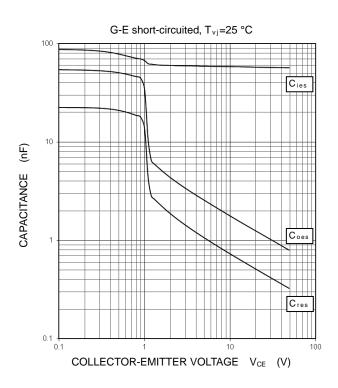


# HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

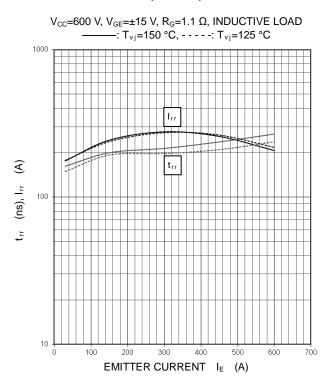


#### **PERFORMANCE CURVES**

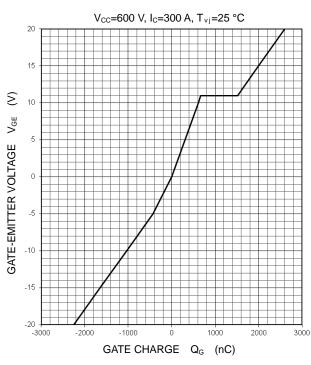
# CAPACITANCE CHARACTERISTICS (TYPICAL)



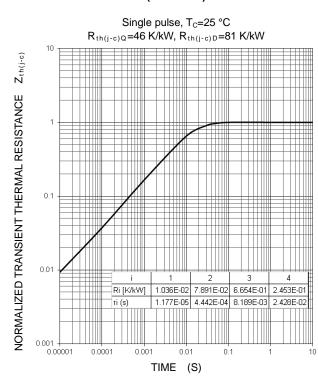
# FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



# GATE CHARGE CHARACTERISTICS (TYPICAL)



# TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

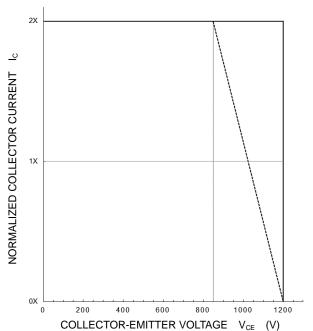
HIGH POWER SWITCHING USE

INSULATED TYPE

#### **PERFORMANCE CURVES**

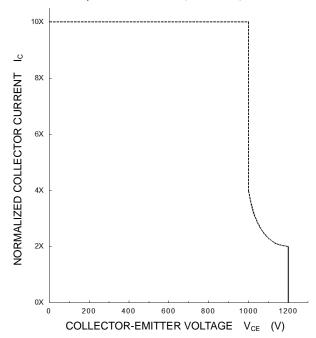
#### TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)

 $\begin{array}{c} V_{\text{CC}}\!\!\leq\!\!850\text{ V, }V_{\text{GE}}\!\!=\!\!\pm\!15\text{ V, }R_{\text{G}}\!\!=\!\!1.1\text{--}22\,\Omega,\\ -\!-\!-\!-\!:T_{\nu j}\!\!=\!\!25\text{--}150\text{ °C (Normal load operations (Continuous)}\\ -\!-\!-\!-\!:T_{\nu j}\!\!=\!\!175\text{ °C (Unusual load operations (Limited period)} \end{array}$ 



# SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)

 $V_{CC}{\le}800$  V,  $V_{GE}{=}{\pm}15$  V,  $R_{G}{=}1.1{\sim}22$   $\Omega,$   $T_{vj}{=}$  25  ${\sim}$  150 °C,  $t_W{\le}8$   $\mu s,$  Non-Repetitive



HIGH POWER SWITCHING USE INSULATED TYPE

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